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**Fiksni upori za uporabo v elektronski opremi - 2-20. del: Neizpolnjena podrobna specifikacija - Tankoplastni upori nizke moči s priključki za montažo skozi prehodne luknje tiskanih vezij (THT) za visokozmogljivo elektronsko opremo, razvrstitvena raven P, ali za visokozmogljivo in zelo zanesljivo elektronsko opremo, razvrstitvena raven R**

Fixed resistors for use in electronic equipment - Part 2-20: Blank detail specification: Low-power film resistors with leads for through-hole assembly on circuit boards (THT), for high-performance electronic equipment, classification level P, or for high-performance and high-reliable electronic equipment, classification level R

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**Document Preview**

Résistances fixes utilisées dans les équipements électroniques - Partie 2-20: Spécification particulière-cadre: Résistance à broches à couche, à faible dissipation, pour assemblage par trous traversants sur cartes de circuit imprimé (THT), pour les équipements électroniques de haute performance (niveau de classification P) ou pour les équipements électroniques de haute performance et de haute fiabilité (niveau de classification R)

**Ta slovenski standard je istoveten z: prEN IEC 60115-2-20:2025**

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**ICS:**

31.040.10	Fiksni upor	Fixed resistors
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<b>oSIST prEN IEC 60115-2-20:2026</b>	<b>en,fr,de</b>
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# 40/3266/CDV

COMMITTEE DRAFT FOR VOTE (CDV)

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IEC TC 40 : CAPACITORS AND RESISTORS FOR ELECTRONIC EQUIPMENT

SECRETARIAT:

Netherlands

SECRETARY:

Mr Ronald Drenthen

OF INTEREST TO THE FOLLOWING COMMITTEES:

HORIZONTAL FUNCTION(S):

ASPECTS CONCERNED:

☒ SUBMITTED FOR CENELEC PARALLEL VOTING

☐ NOT SUBMITTED FOR CENELEC PARALLEL VOTING

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TITLE:

**Fixed resistors for use in electronic equipment - Part 2-20: Blank detail specification: Low-power film resistors with leads for through-hole assembly on circuit boards (THT), for high-performance electronic equipment, classification level P, or for high-performance and high-reliable electronic equipment, classification level R**

PROPOSED STABILITY DATE: 2033

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

**FIXED RESISTORS FOR USE IN ELECTRONIC EQUIPMENT –****Part 2-20: Blank detail specification: Low-power film resistors with leads  
for through-hole assembly on circuit boards (THT),  
for high-performance electronic equipment, classification level P,  
or for high-performance and high-reliable electronic equipment,  
classification level R**

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The text of this International Standard is based on the following documents:

Draft	Report on voting
40/XX/FDIS	40/XX/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.